

EAST Search History**EAST Search History (Prior Art)**

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8	("5395446").URPN.	USPAT	OR	ON	2009/12/21 11:50
L2	14	("4350174" "4540278" "4788994" "4822639" "4838979" "5095848" "5209180" "5395446" "5426057" "5545076" "5608943" "5706843" "5718763" "5766354").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/12/21 11:56
L3	6	("6182675").URPN.	USPAT	OR	ON	2009/12/21 11:58
L4	23	("3760822" "3810779" "3933187" "4060097" "4075974" "4501527" "4564280" "4584886" "4634497" "4695327" "4705951" "4746256" "4790262" "4800836" "4816638" "4822639" "4827954" "4838979" "4886412" "4891087" "4891488" "4944860").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/12/21 11:58

L5	3	recovery adj tool with (drop droplet sphere)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/12/21 11:59
L6	17	(US-20090151480-\$). did. or (US-7471762-\$ or US-5633172-\$ or US-5527707-\$ or US-5395446-\$ or US-4564280-\$ or US-6182675-\$). did. or (WO-2005073692-\$ or EP-1710555-\$). did. or (JP-2005236145-\$ or JP-2000332072-\$ or JP-2000186988-\$ or JP-11166882-\$ or JP-05283498-\$ or JP-05256749-\$). did. or (JP-2006108364-\$ or JP-2000107672-\$). did.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2009/12/21 12:05
L7	3	6 and recovery adj tool	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/12/21 12:05
L9	2742	(134/902).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2009/12/21 14:11
L10	0	9 and recovery adj tool	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/12/21 14:11
L11	87	9 and inspect\$3 with (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/12/21 14:12
L12	41	9 and inspect\$3 with (substrate wafer) and (drop bead droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/12/21 14:12
S1	7	"584822".ap.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/17 13:08

S2	1	S1 and recovery adj tool	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/17 13:09
S3	59	recovery adj tool and substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 16:37
S4	10	recovery adj tool and substrate and inspection	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 16:38
S5	3	(US-20090151480-\$). did. or (WO-2005073692-\$ or EP-1710555-\$).did.	US-PGPUB; EPO	OR	ON	2009/09/27 16:41
S6	3	S5 and recovery adj tool	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 16:42
S7	3	recovery adj tool with (drop droplet sphere)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 16:43
S8	152	substrate near3 inspect\$3 same (drop droplet sphere)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 16:59
S9	2	substrate near3 inspect\$3 with (tube cylindrical cone conical) same (drop droplet sphere)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:00
S10	2	substrate with inspect \$3 with (tube cylindrical cone conical) same (drop droplet sphere) and recovery	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:33
S11	872	substrate with impurit \$3 same (drop droplet sphere)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:35
S12	844	substrate with impurit \$3 same (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:35

S13	707	semiconductor and substrate with impurity \$3 same (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:35
S14	330	semiconductor with substrate with impurity \$3 same (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:35
S15	140	semiconductor with substrate with impurity \$3 with (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:35
S16	17	semiconductor with substrate with surface near2 impurity \$3 with (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:39
S17	8	("5395446").URPN.	USPAT	OR	ON	2009/09/27 17:40
S18	23	("3760822" "3810779" "3933187" "4060097" "4075974" "4501527" "4564280" "4584886" "4634497" "4695327" "4705951" "4746256" "4790262" "4800836" "4816638" "4822639" "4827954" "4838979" "4886412" "4891087" "4891488" "4944860").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/09/27 17:41

S19	15	(US-20090151480-\$). did. or (US-7471762-\$ or US-5633172-\$ or US-5527707-\$ or US-5395446-\$ or US-4564280-\$).did. or (WO-2005073692-\$ or EP-1710555-\$). did. or (JP-2005236145-\$ or JP-2000332072-\$ or JP-2000186988-\$ or JP-11166882-\$ or JP-05283498-\$).did. or (JP-2006108364-\$ or JP-2000107672-\$). did.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:54
S20	3	S19 and (groove through adj hole)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 17:54
S21	2	S19 and negative adj pressure	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 18:43
S22	30	"256749"	JPO; DERWENT	OR	ON	2009/09/27 18:47
S23	1	"05256749"	JPO; DERWENT	OR	ON	2009/09/27 18:48
S24	2	"05283498"	JPO; DERWENT	OR	ON	2009/09/27 18:49
S25	1163	(73/865.8).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2009/09/27 19:23
S26	1	S25 and (wafer substrate semiconductor) with impurit\$3 same (drop droplet)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2009/09/27 19:24

EAST Search History (Interference)

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L8	15	(73/865.8).CCLS.	UPAD	OR	OFF	2009/12/21 14:08
L13	0	(134/902).CCLS.	UPAD	OR	OFF	2009/12/21 14:27

12/21/09 2:29:33 PM

**C:\ Documents and Settings\ JFitzgerald\ My Documents\ EAST\ Workspaces\ 73\ 10 series
\ 10584822_recovery_tool_GG.wsp**